
Electronic Structure and Morphology of Graphene Films on SiC

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(previously)

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Structure of Graphene, 2:30PM - 3:06PM
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- Collaborators:

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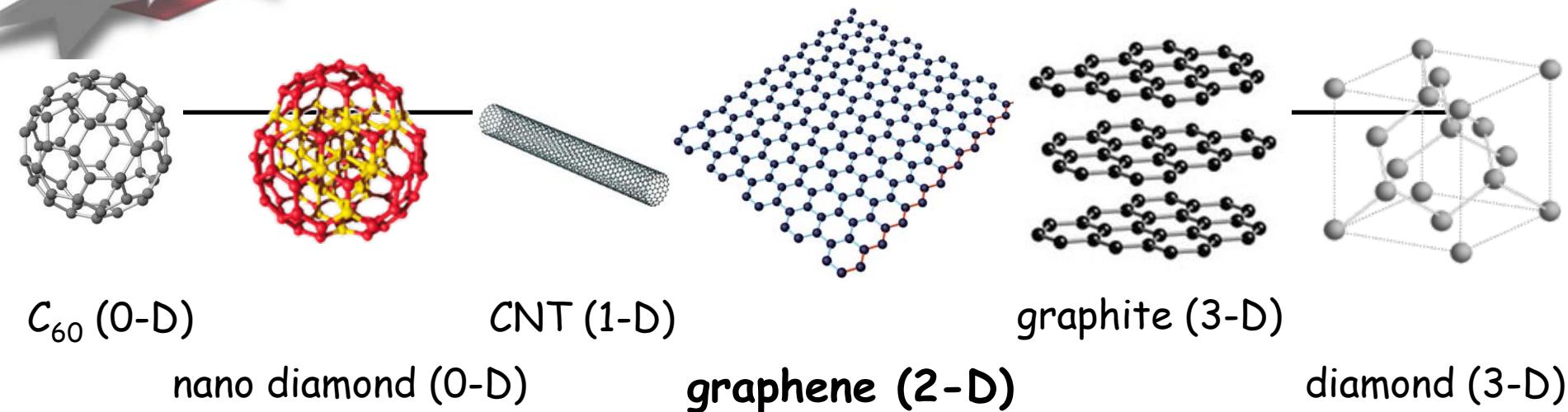
- Sandia National Laboratories
 - Sandia is a multiprogram laboratory operated by Sandia Corporation, a Lockheed Martin Company, for the U.S. Department of Energy's National Nuclear Security Administration under contract DE-AC04-94AL85000.



MAX-PLANCK-GESELLSCHAFT

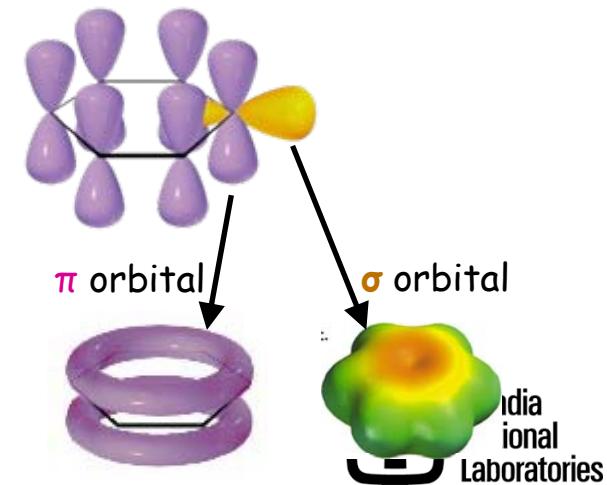
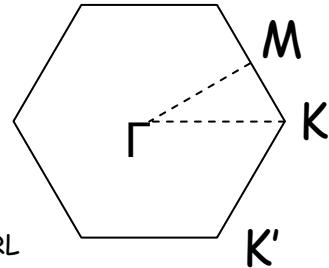
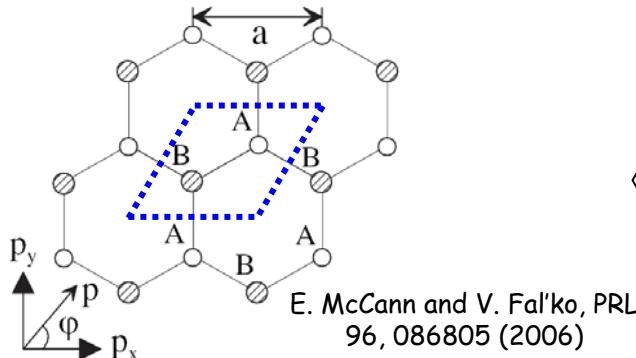


Graphene and Allotropes of Carbon

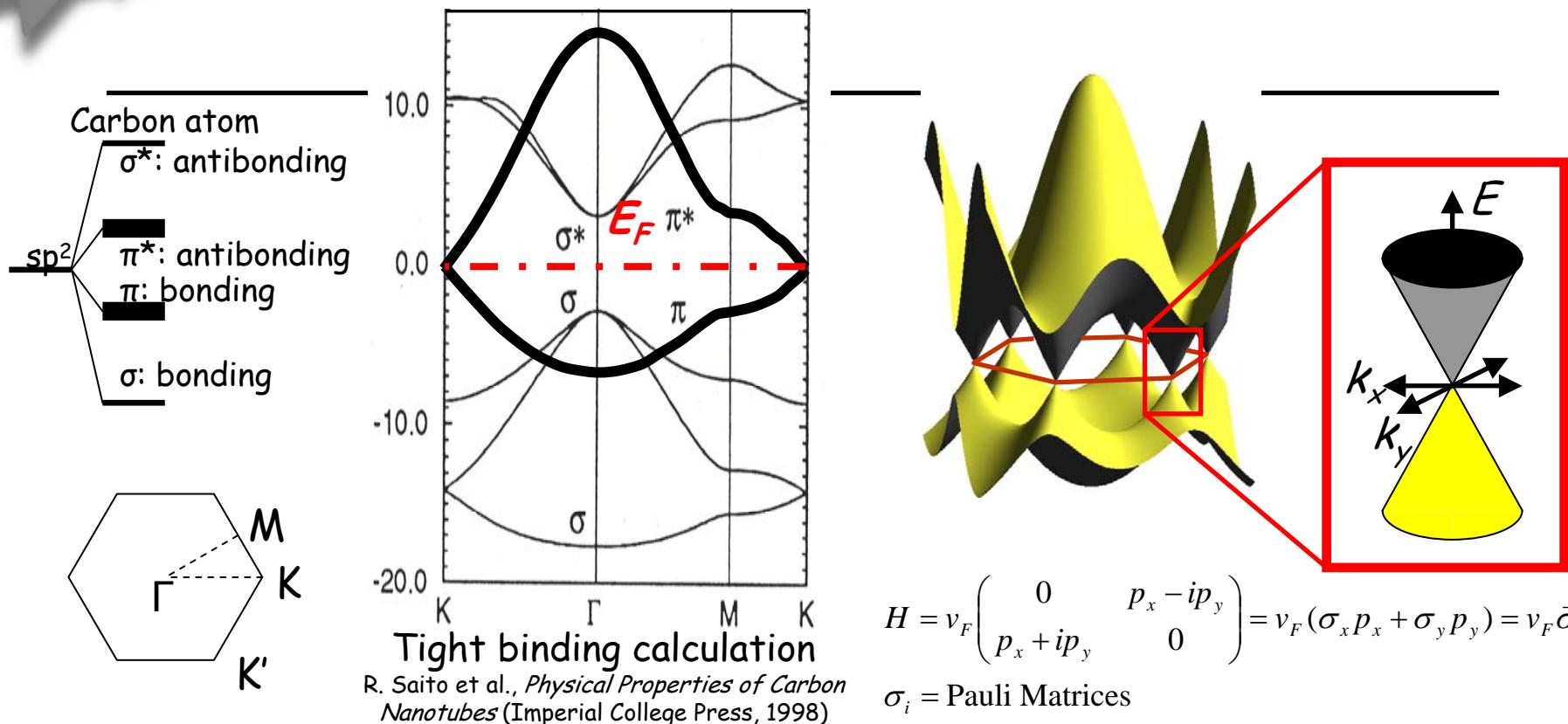


- **Graphene**

- **sp^2 hybridized carbon in honeycomb structure**
 - Building block for graphite, carbon nanotube, C_{60} etc.
- **Delocalized π and σ orbitals**
- **K and K' points equivalent**
 - Hexagonal Brillouin zone



Unique Electronic Structure of Graphene



- $E(k)$ linear around K
 - Linear, gapless, conical bands centered at K points
 - Formal equivalency with Dirac's equation for massless, relativistic particle
 - "Dirac Fermions"
 - Realization of desktop QED experiments (?)

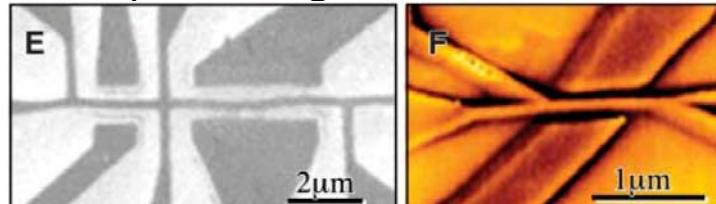
Technological Interests toward Graphene

- High electron mobility ($25,000 \text{ cm}^2/\text{V}\cdot\text{sec}$)*
- Ballistic transport: long coherent length ($> 1\mu\text{m}$)*
- High current capacity
- Micro-nano patterning applicable
 - Semiconductor processing technology
- ➔ High-speed electronics
- ➔ Terahertz source
- ➔ Sensitive gas sensors
- ➔ New device principles
 - Klein tunneling, Veselago lensing etc.

• Graphene films produced by scalable synthesis route

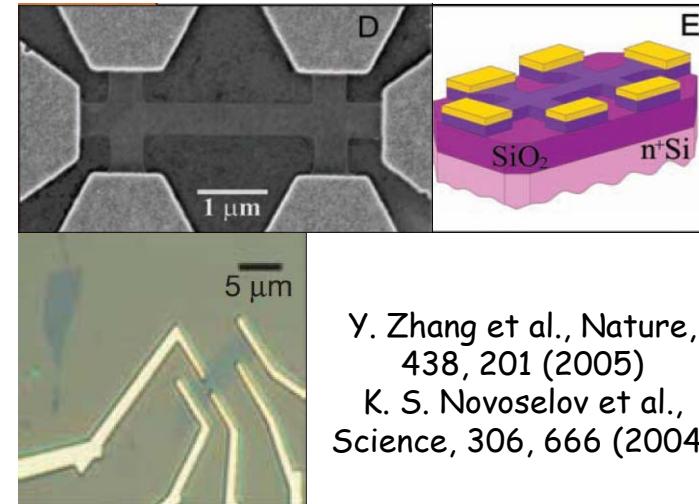
➔ Lead us to study graphene films on SiC

Epitaxial growth on SiC



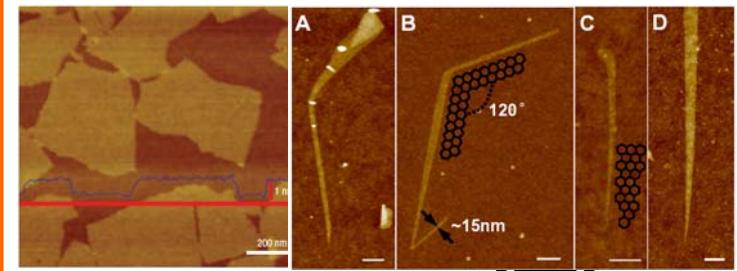
*C. Berger et al., Science, 312, 1191 (2006)

Mechanical exfoliation



Y. Zhang et al., Nature, 438, 201 (2005)
K. S. Novoselov et al., Science, 306, 666 (2004)

Chemical exfoliation



D. Li et al., Nature, published online (2008)
X. Li et al., Science express (2008)



Outline

1. Electronic band structure of single and multilayer graphene

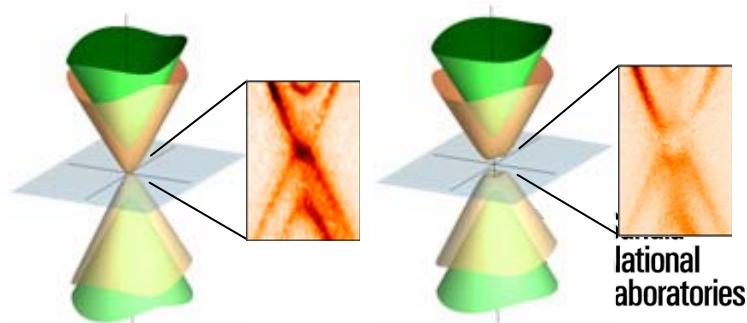
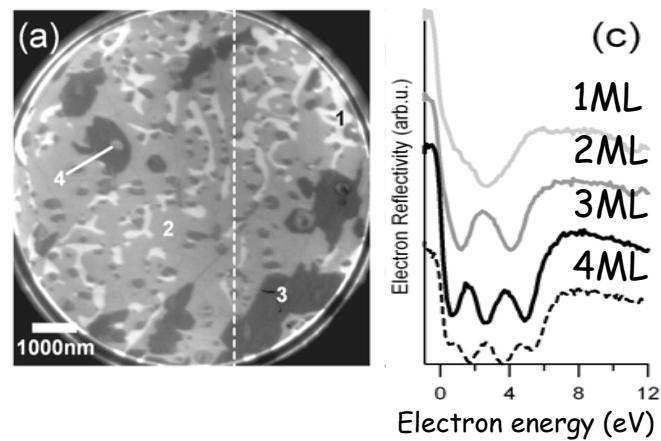
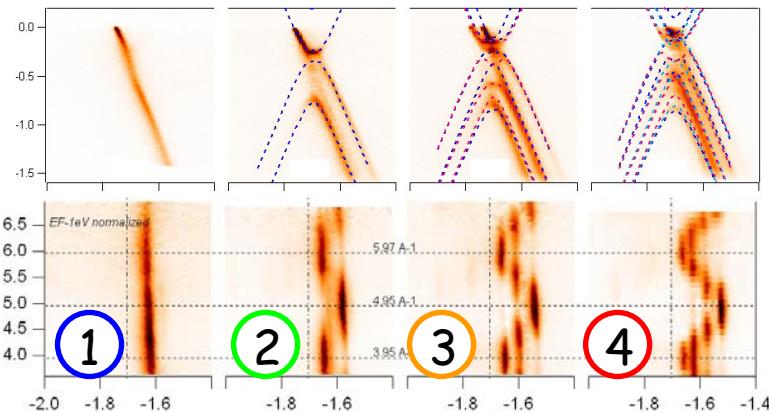
- Transition from 2D (single) to 3D (multilayer)?
- Potential and carrier concentration profiles in multilayer
 - Interlayer interaction and electron screening

2. Morphology of graphene films on SiC

- Determining domain size and local thickness
 - Importance of interface-carbon layer on the formation of graphene

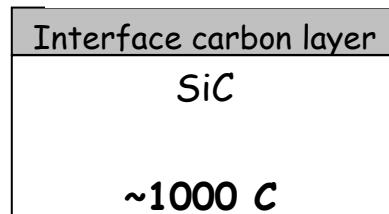
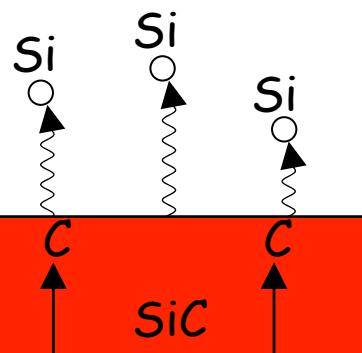
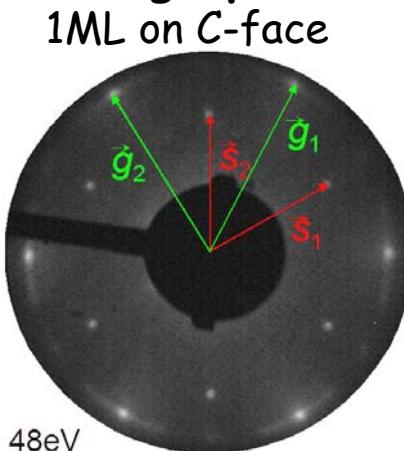
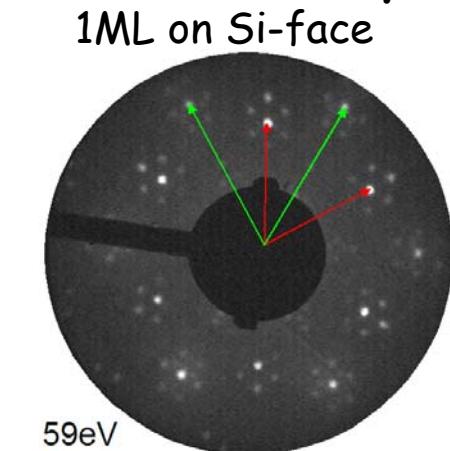
3. Controlling the electronic structure in graphene bilayer

- Gap at E_D dependent on the electron potential of each layer
 - Switching functionality

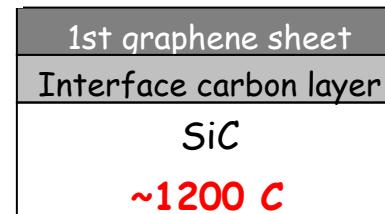


Epitaxial graphene films on SiC

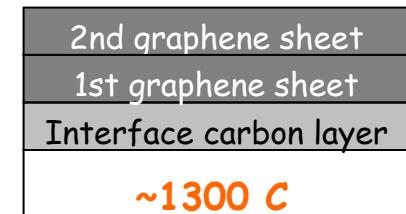
- Thermal decomposition and Si sublimation of SiC substrate (graphitization)
- SiC(0001) (Si-face)
 - Azimuthally ordered graphene films



Interface layer formation

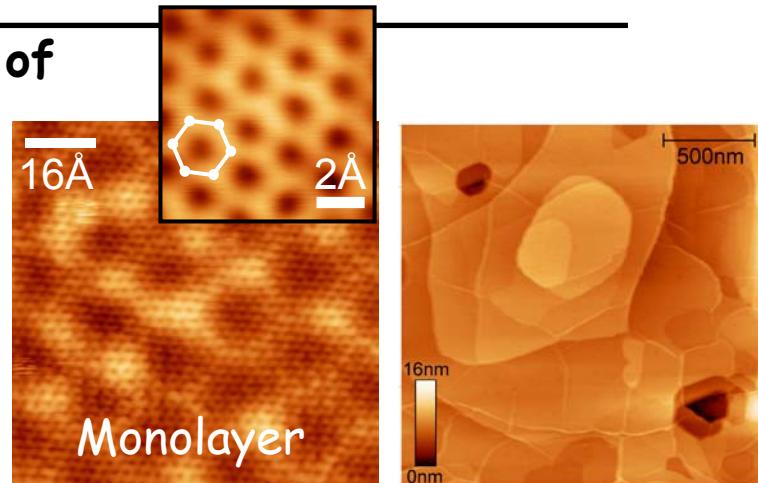


1st graphene sheet formation

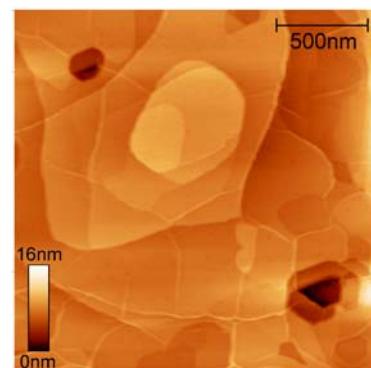


2nd graphene sheet formation

Higher temp/longer anneal



STM on graphene
V. W. Brar et al.,
Appl. Phys. Lett., 91,
122102, 2007



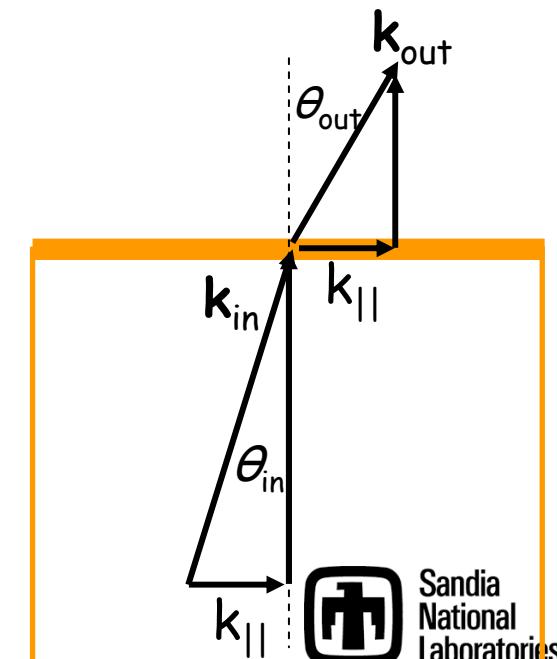
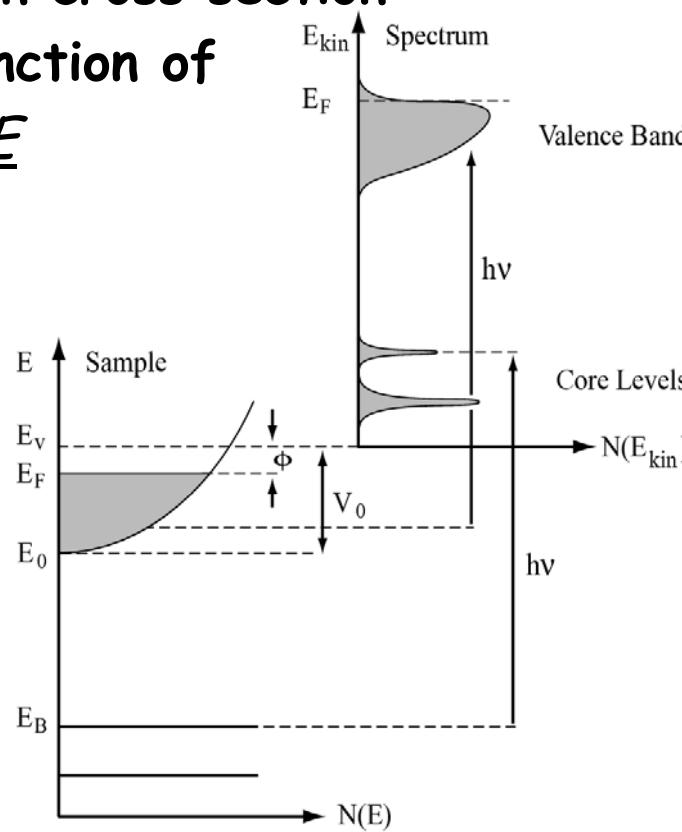
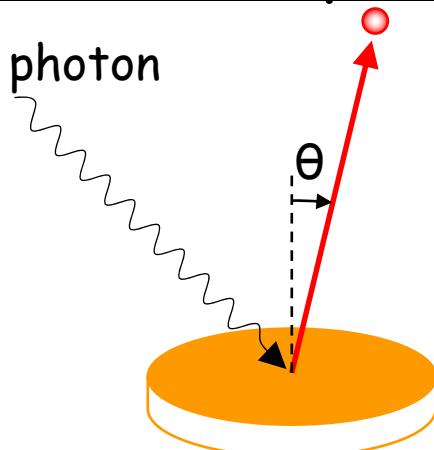
Th. Seyller et al.,
unpublished

Photoemission spectroscopy

- Directly tool to measure electronic band structure
 - Detect photoelectron
 - Photoemission intensity
 - = density of states (number of electrons) \times photoemission cross section
 - Spectra as a function of electron energy E
- Spectra as a function of momentum \underline{k}
- Momentum conserved in translational symmetry

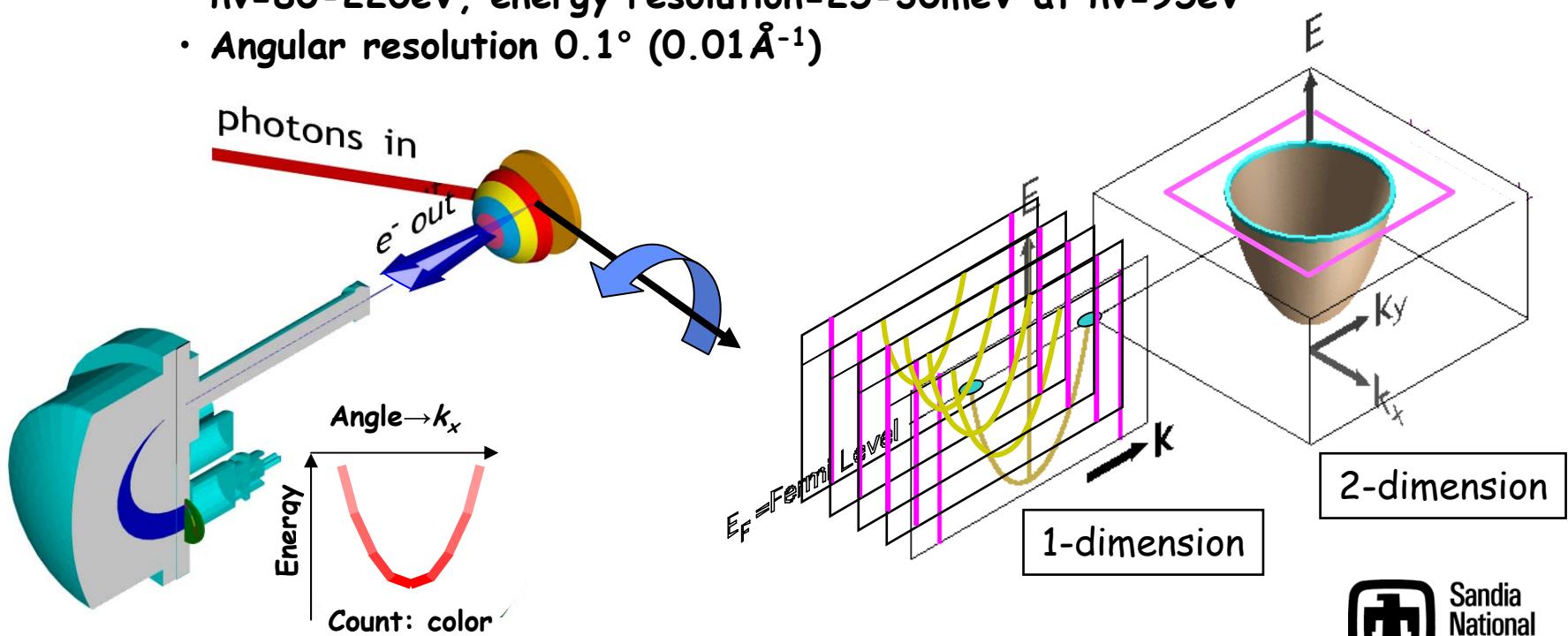
$$k_{\parallel} = \sin \theta_{out} \sqrt{\frac{2m}{\hbar^2} E_{kin}}$$

Photoemission process

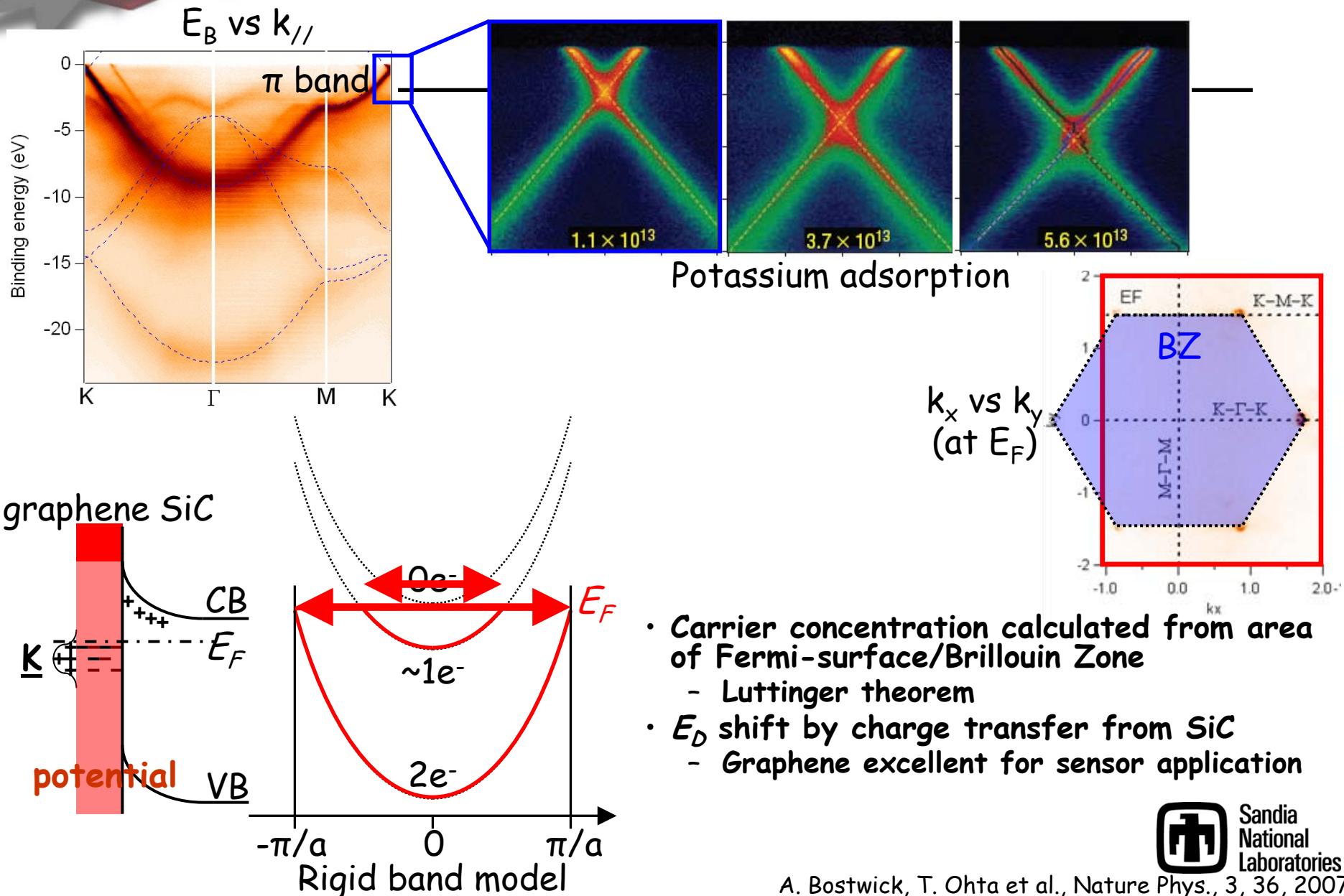


Photoemission spectroscopy (cont'd)

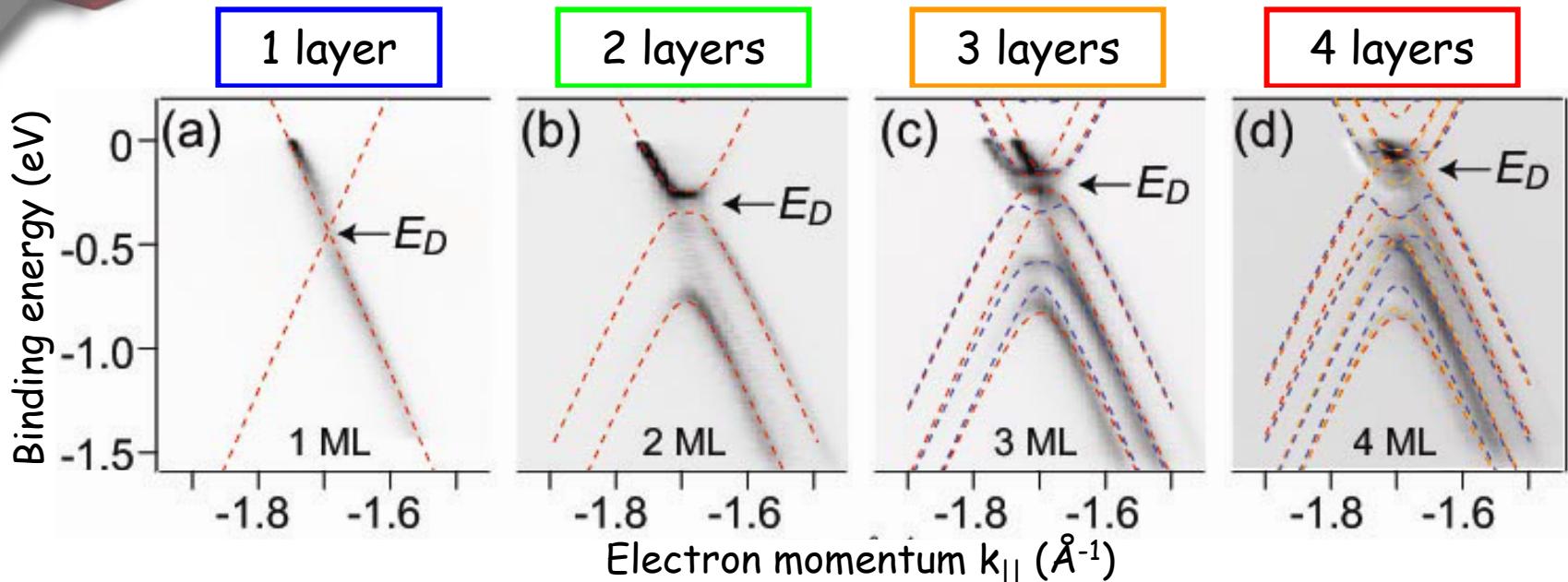
- Electronic band structure (dispersion relation E vs k)
 - Angle resolved photoemission
 - Spectra: DOS as a function of electron energy E and momentum k
 - Light source: synchrotron radiation, ALS BL7
 - $h\nu=80-220\text{eV}$, energy resolution=25-30meV at $h\nu=95\text{eV}$
 - Angular resolution 0.1° (0.01\AA^{-1})



Electr. Structure of Graphene Films

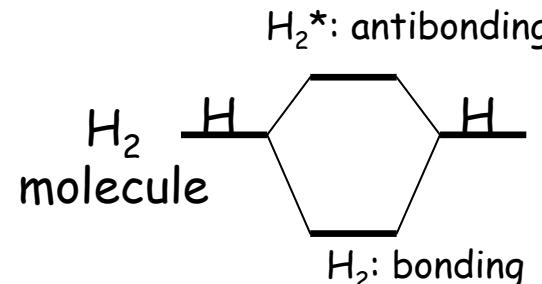


Evolution of π Band in Multilayer

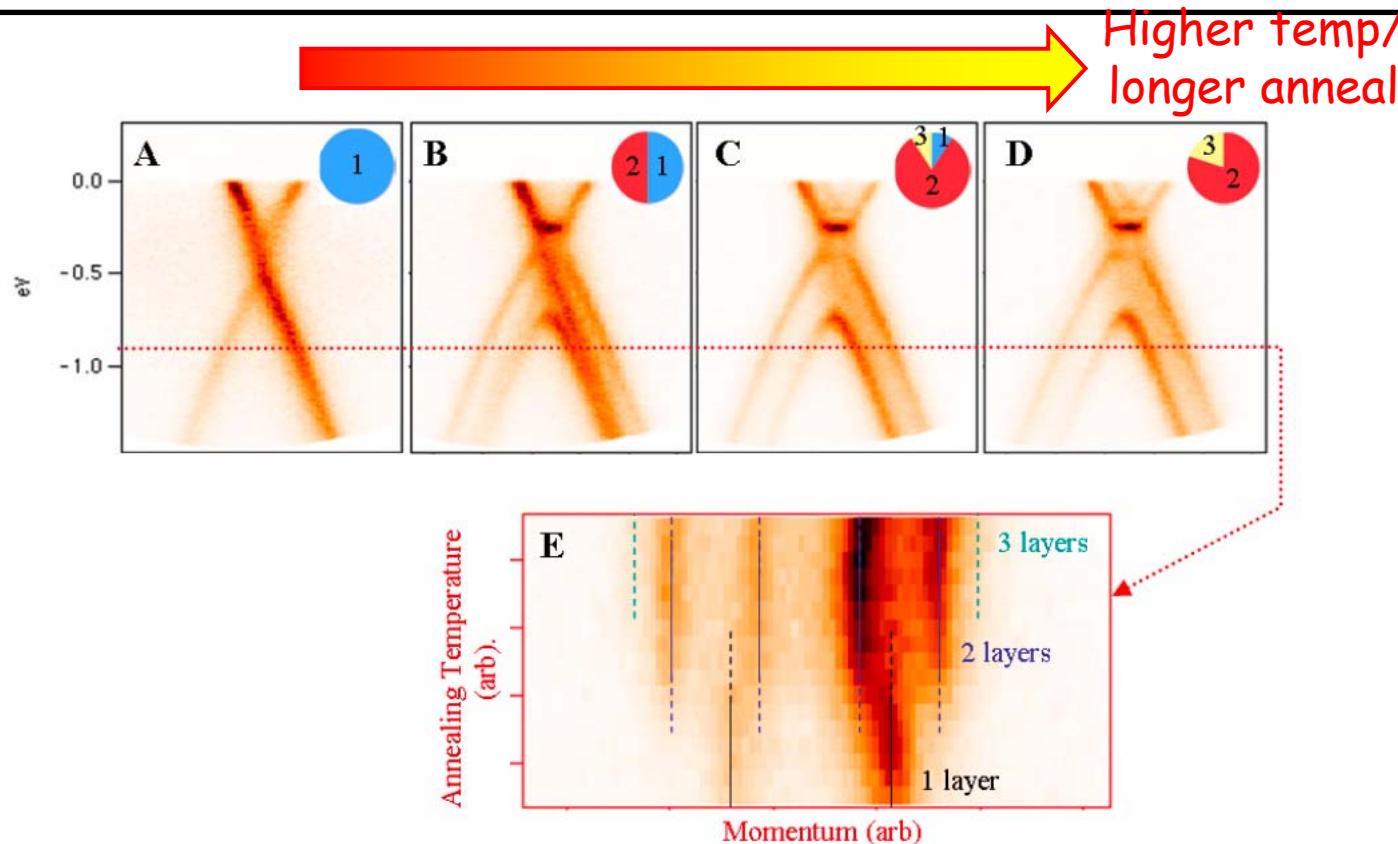


- π band splitting due to interlayer interaction
- E_D (crossing point) shift smaller for thicker graphene film
 - Same total charge transfer from SiC, but more bands crossing E_F
- Effect of stacking sequence
 - **Bernal (ABA)** and **rhombohedral (ABC)** stackings for 3 layers
 - **Bernal type** stackings (ABAB or ABAC) for 4 layers
 - Graphite: **Bernal (ABAB)** stacking \Rightarrow toward bulk graphite

Tight binding Hamiltonian from F. Guinea et al., cond-mat/0604396;
E. McCann cond-mat/0608221

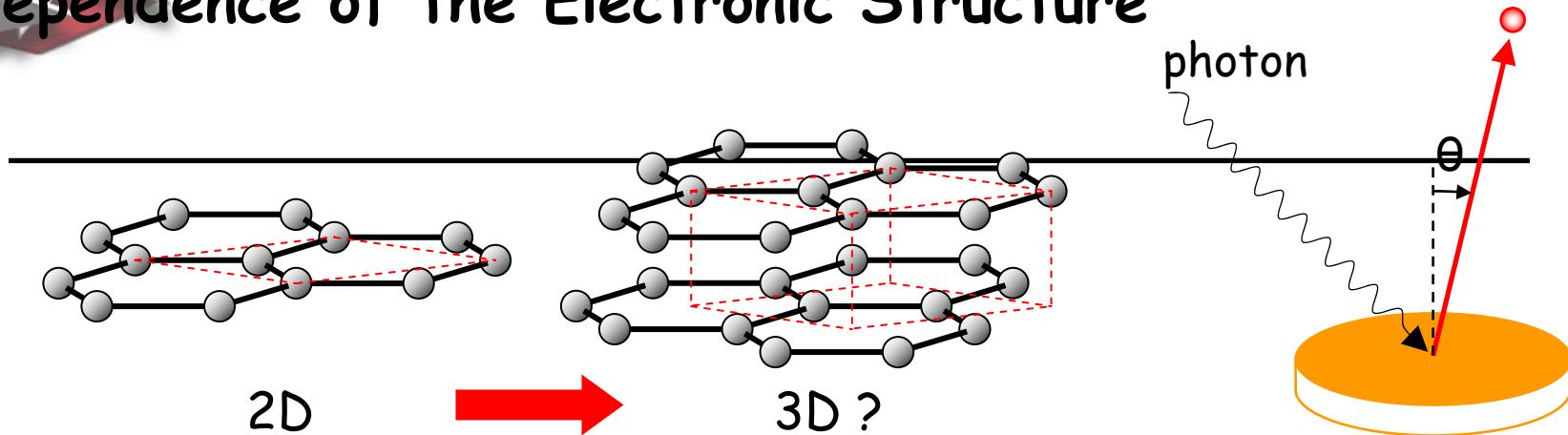


Evolution of π Band as a function of Annealing Temperature



- Thicker layers by higher temperature or longer anneal
- Counting the number of π states to determine the number of layers
- Mixture of $n-1$, n , $n+1$ layers beyond 2 layers
 - Isolation of a thicker layer component by subtraction of photoemission pattern

k_{\perp} Dependence of the Electronic Structure

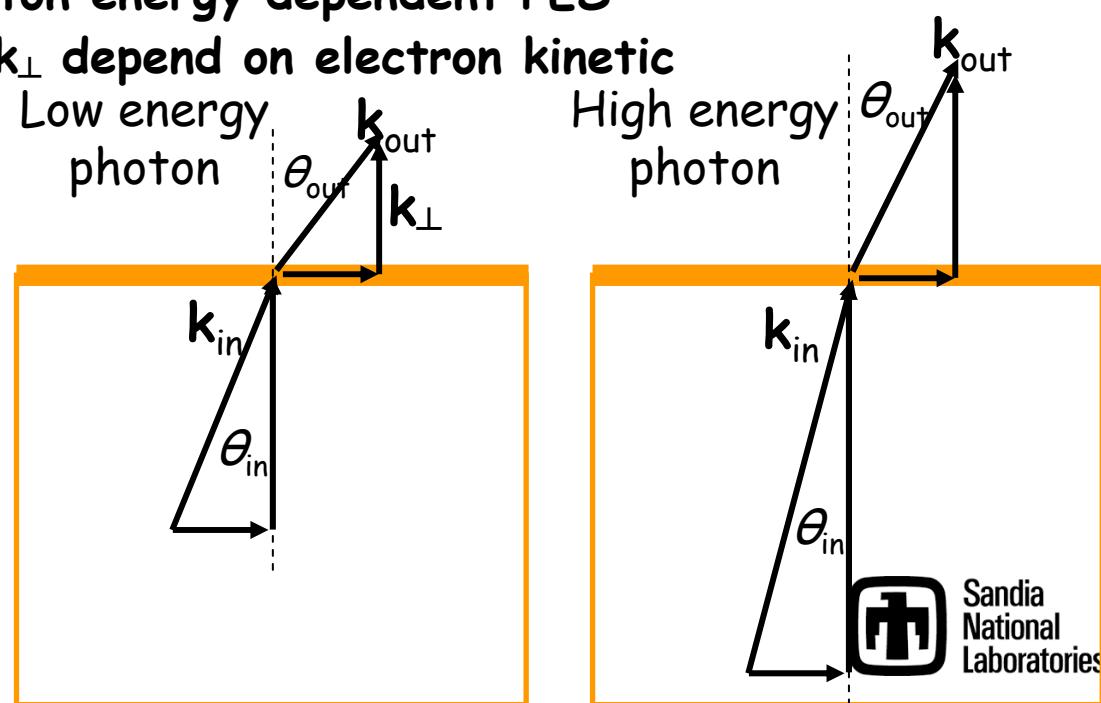


- k_{\perp} can be tuned by photon energy dependent PES
 - Electron momentum k_{\perp} depend on electron kinetic energy

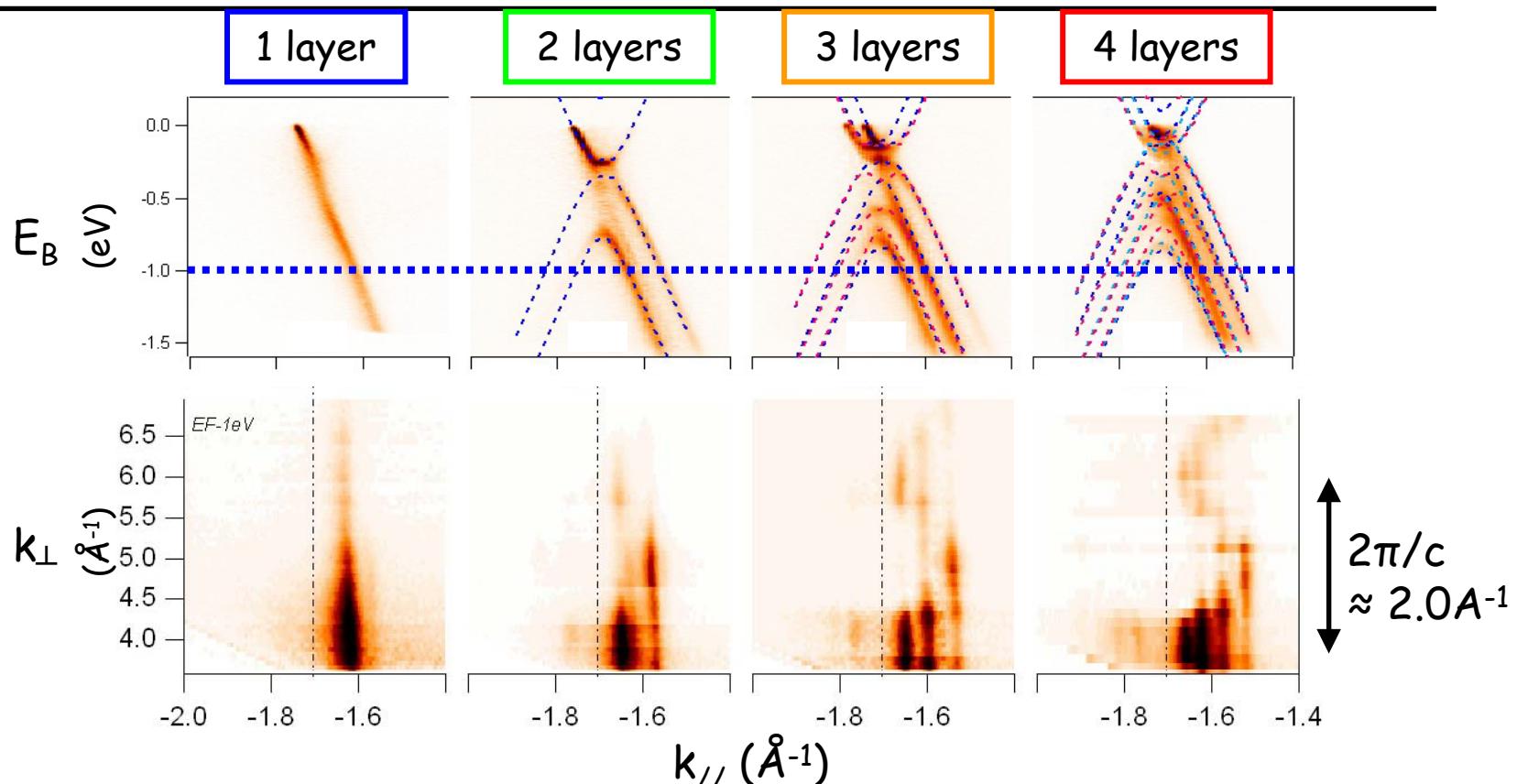
$$E_{kin} = h\nu - \phi - E_B$$

$$k_{out} = \sqrt{\frac{2m}{\hbar^2} E_{kin}}$$

$$k_{in} = \sqrt{\frac{2m}{\hbar^2} (E_{kin} + V_0)}$$

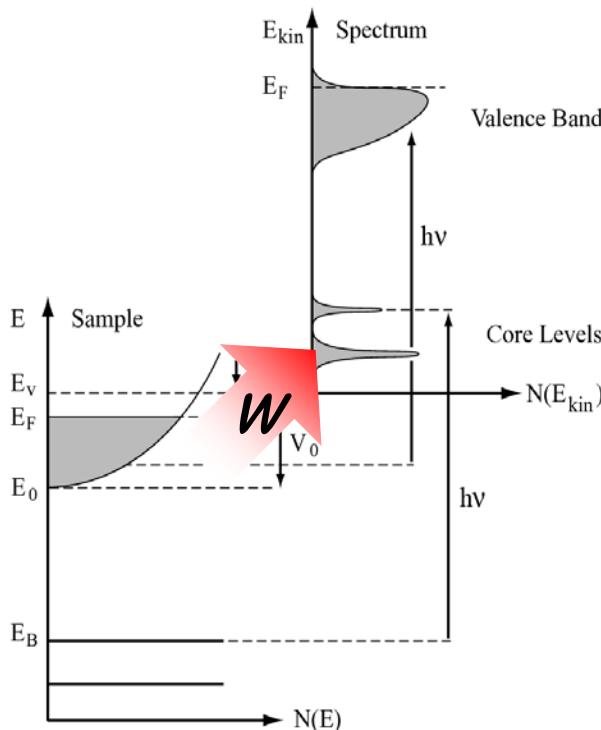
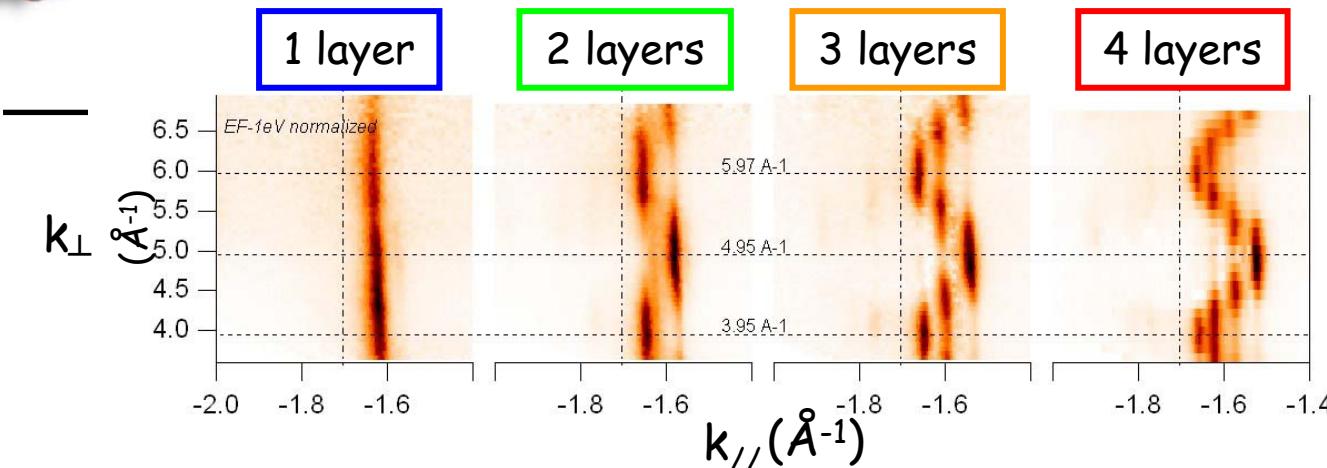


2D to 3D Transition



- Non-dispersing π bands: 2-D system
- Alternating photoemission intensity from split π bands
 - Periodicity matches to interlayer distance of bulk graphite

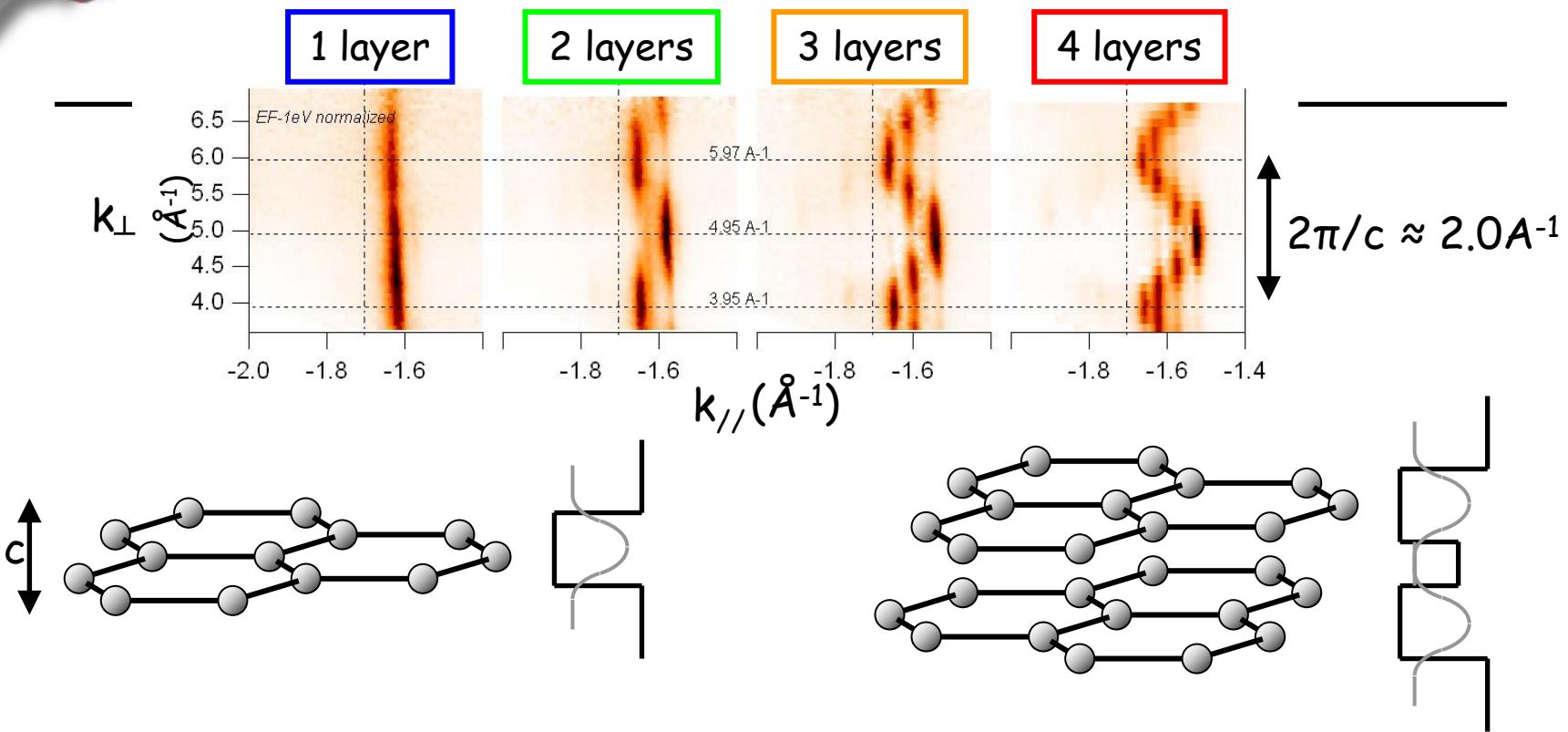
2D to 3D Transition (cont'd)



$w \propto \frac{2\pi}{\hbar} |M_{fi}|^2 \delta(E_f - E_i - \hbar\omega)$
w: transition probability (for photoemission)
 H_{int} : interaction between electromagnetic field and electron
 M_{fi} : transition matrix
Projection of initial states onto final states
Final state: free-electron approximation

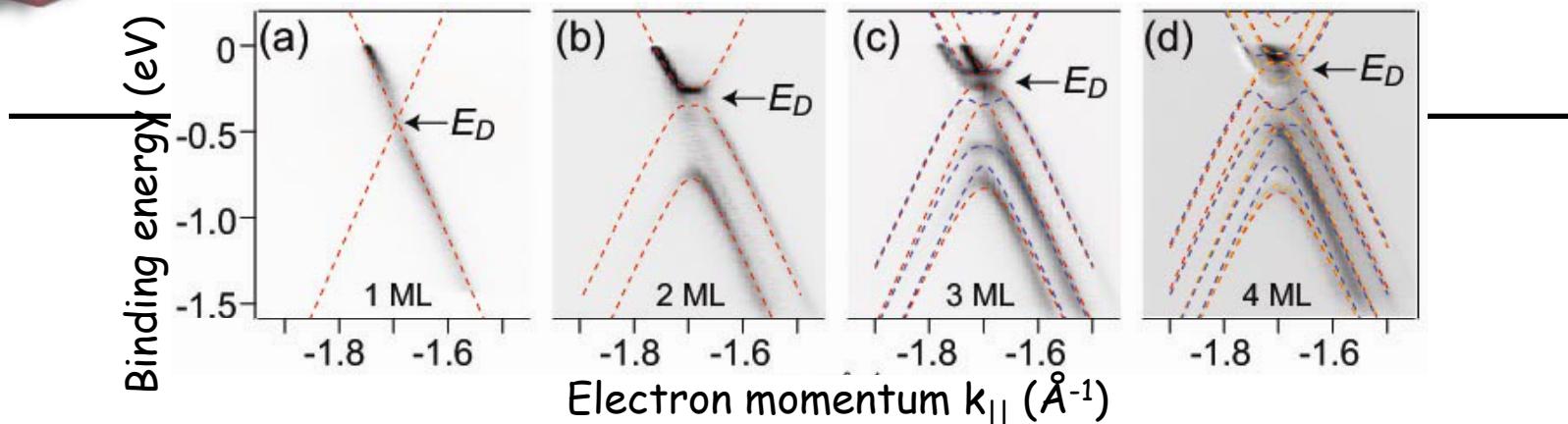
- What makes $|M_{fi}|^2 |\langle \psi_f | H_{int} | \psi_i \rangle|^2$
 ➔ Character of initial state wave function

2D to 3D Transition (cont'd)



- Intensity oscillation matches out-of-plane periodicity of graphene layers
 - ➔ Eventually develops into k_{\perp} band dispersion for infinite thickness (3D material)
- ➔ Transition from 2D to 3D by interlayer interaction
 - Interference of the wave functions in out-of-plane direction
 - Analogous to maximum photoemission intensity for quantum well states and surface states near vertical transition

TB Modeling of π Band for Multilayer



- Single layer

$$H = \begin{pmatrix} 0 & v_F \pi^\dagger \\ v_F \pi & 0 \end{pmatrix}, \quad \pi = p_x + i p_y$$

- Multilayer

- Bernal and rhombohedral stackings

$$H = \begin{pmatrix} \alpha_1 & \beta & & & & \\ \beta^T & \alpha_2 & \beta^T & & & \\ & \beta & \alpha_3 & \beta & & \\ & & \beta^T & \alpha_4 & \beta^T & \\ & & & \beta & \ddots & \\ & & & & & \alpha_N \end{pmatrix}$$

- TB formalism from

- F. Guinea, A. H. Castro Neto, and N. M. R. Peres, Phys. Rev. B 73, 245426 (2006)

- E. McCann and V. I. Fal'ko, Phys. Rev. Lett. 96, 086805 (2006)

$$\alpha_i \equiv \begin{pmatrix} 0 & v\pi^+ \\ v\pi & 0 \end{pmatrix} \quad \beta \equiv \begin{pmatrix} 0 & 0 \\ \gamma_1 & 0 \end{pmatrix}$$

$$\beta_s \equiv \gamma_1 \begin{pmatrix} 0 & s \\ 1-s & 0 \end{pmatrix}$$

$$s = \begin{cases} 0 & \text{Bernal} \\ 1 & \text{Rhombohedral} \end{cases}$$

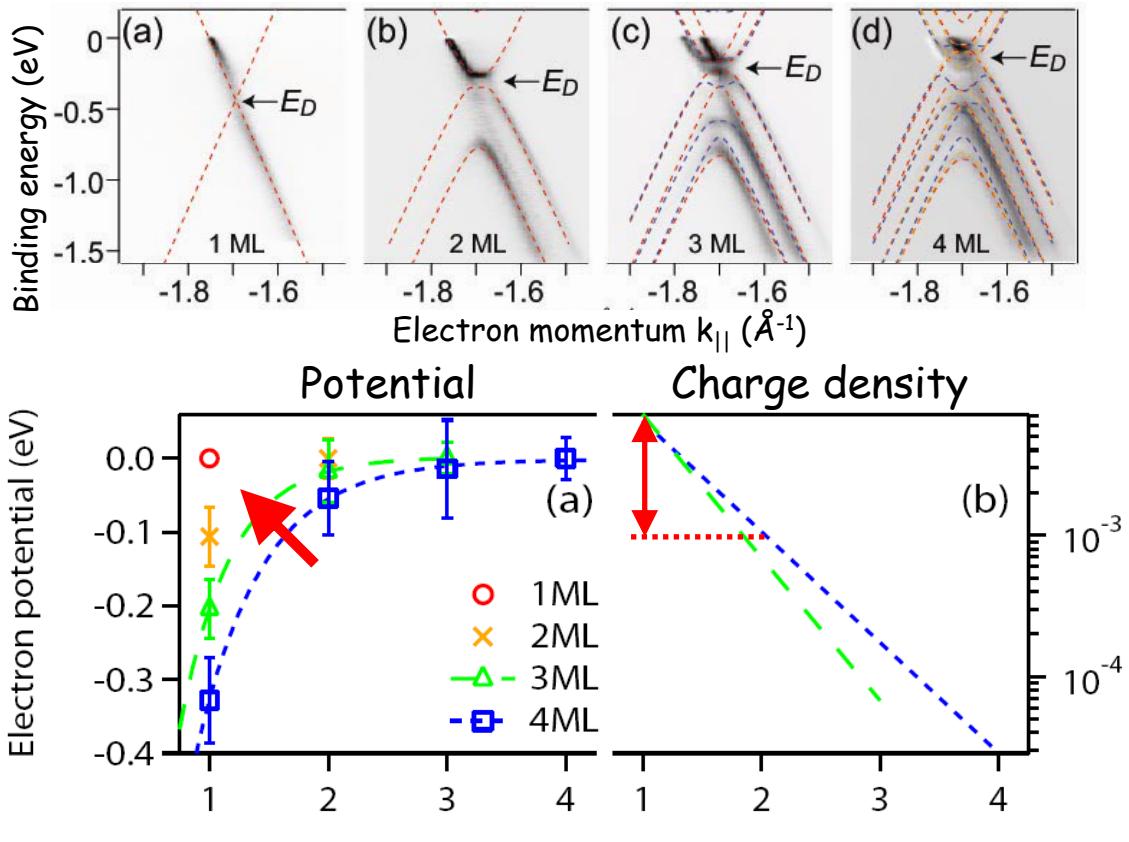
$$\alpha_i \equiv \begin{pmatrix} E_i & v\pi^+ \\ v\pi & E_i \end{pmatrix}$$

$$E_i = \text{onsite Coulomb energy}$$



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Potential and Carrier Concentration Profiles in Multilayer



- Screening length ℓ_s : $\sim 1.4\text{--}1.9\text{\AA}$
 - Exponential decay assumed for potential profile

$$V(z) = \exp\left(-\frac{z}{\ell_s}\right)$$

- More charge carrier than graphite ($3.8\text{--}5\text{\AA}$)
 - Metal(Cu): $\sim 0.5\text{\AA}$, semiconductor(Si): $\text{\AA}\text{--}\mu\text{m}$

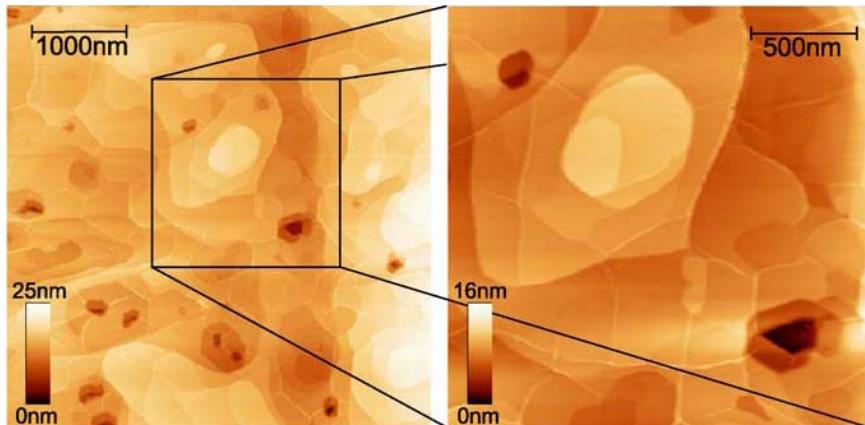
Carrier conc. ($\text{e}^-/\text{unit cell}$)

→ Semiconductor-like electron screening in graphene

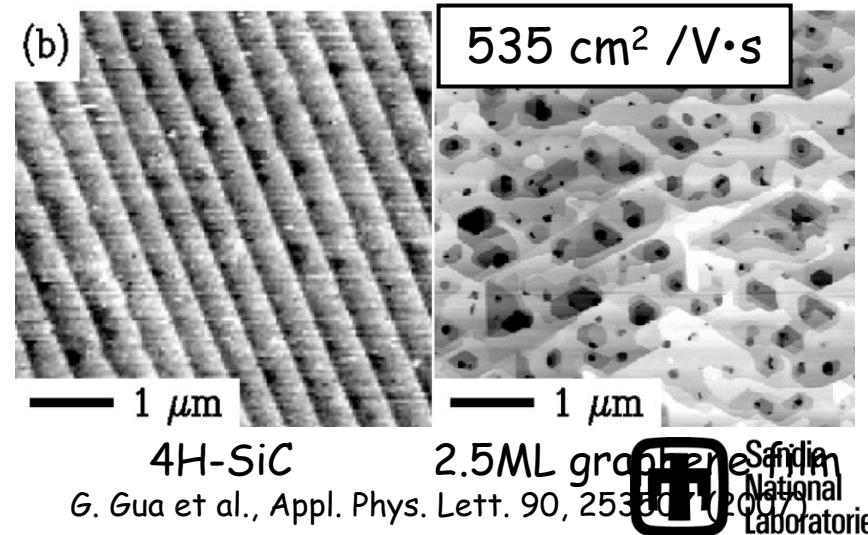
Morphology of Graphene Films on SiC

- Small domain size
- Low carrier mobility
 - Rough morphology of the graphene layer?

➔ Need to improve!



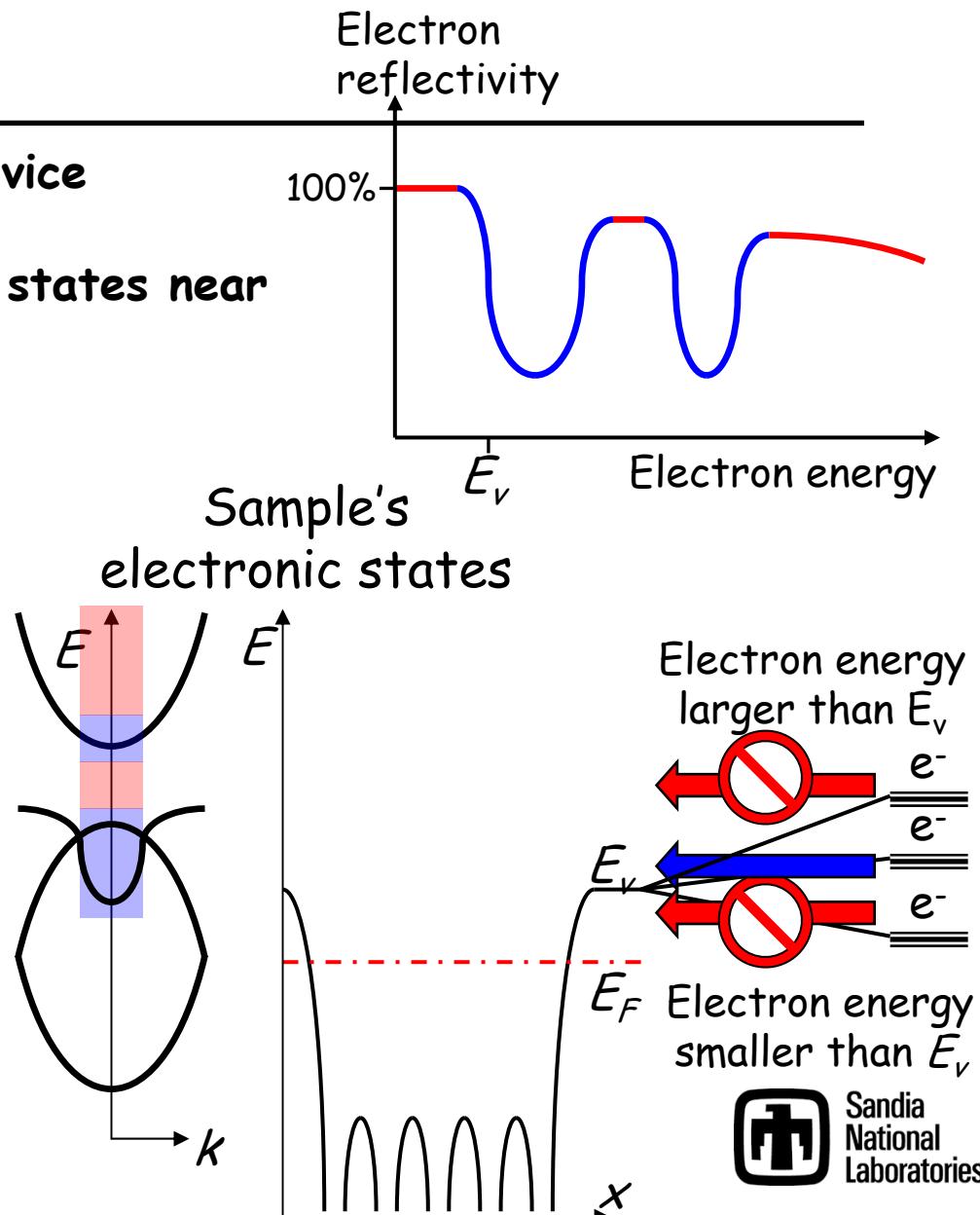
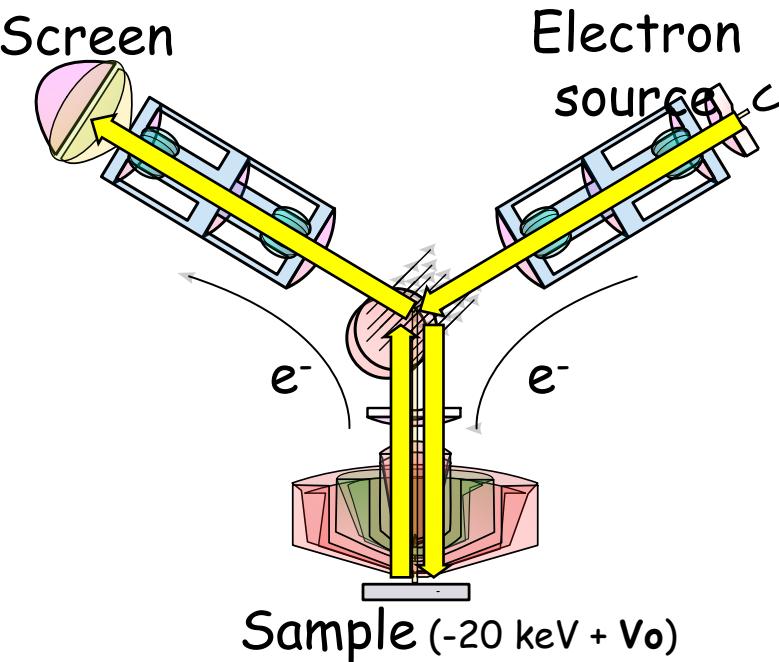
2nm thick graphene film
Th. Seyller et al., Surface Science 600 (2006) 3906



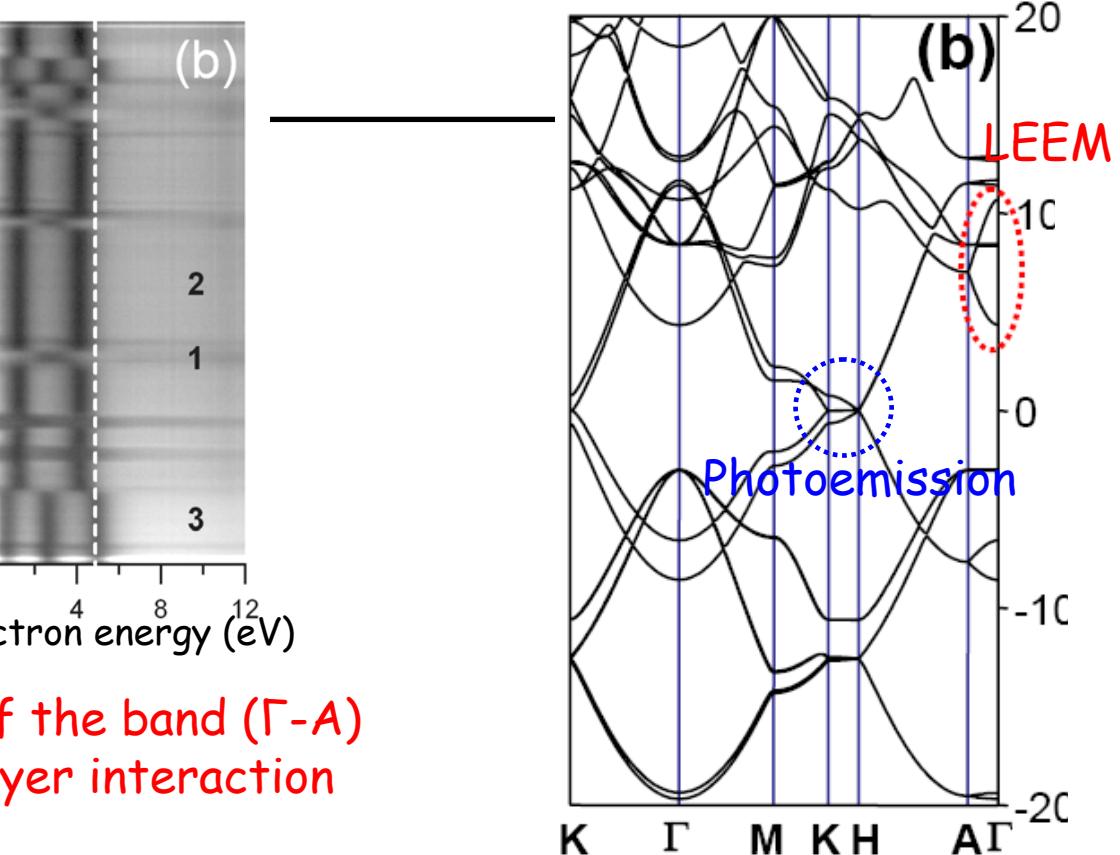
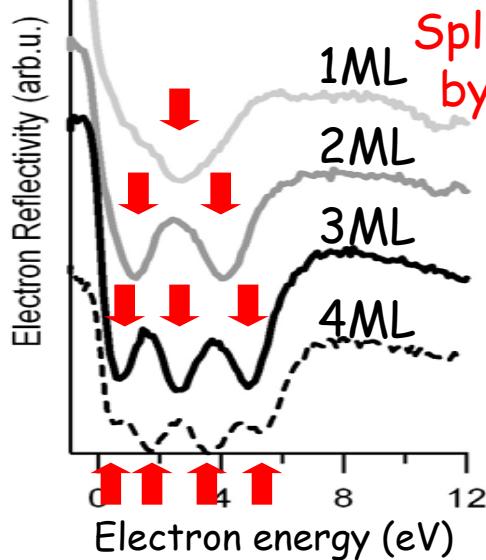
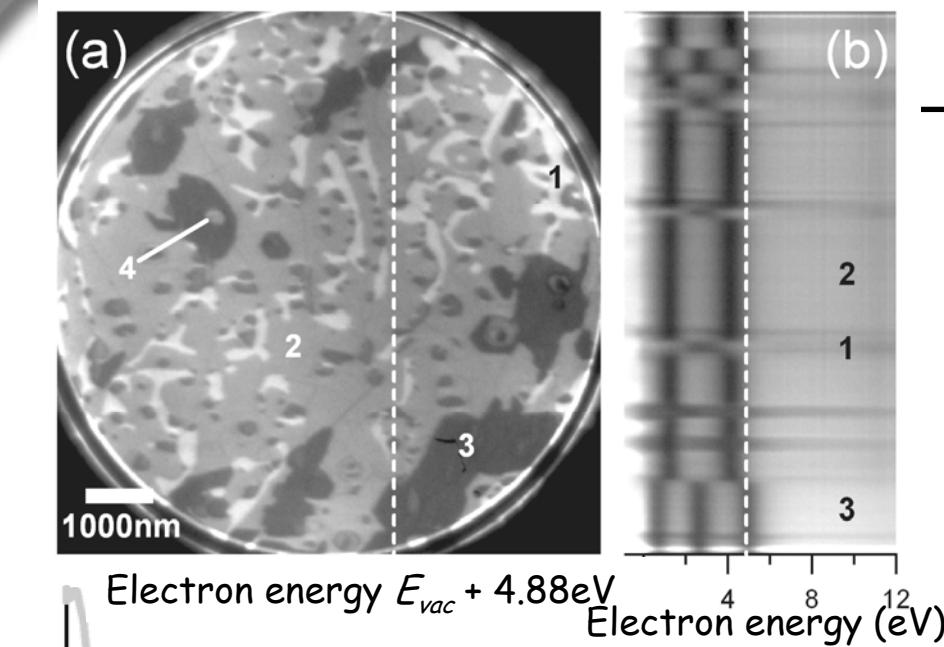
4H-SiC 2.5ML graphene
G. Gua et al., Appl. Phys. Lett. 90, 253501 (2007)
Sandia National Laboratories

LEEM Contrast and LEEM I-V

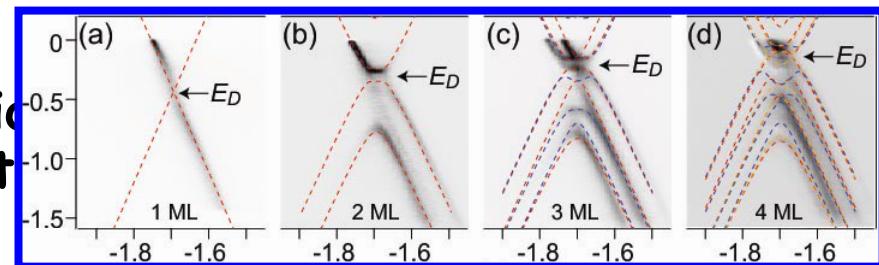
- Morphology: important for device fabrication
- Probing unoccupied electronic states near Brillouin zone center



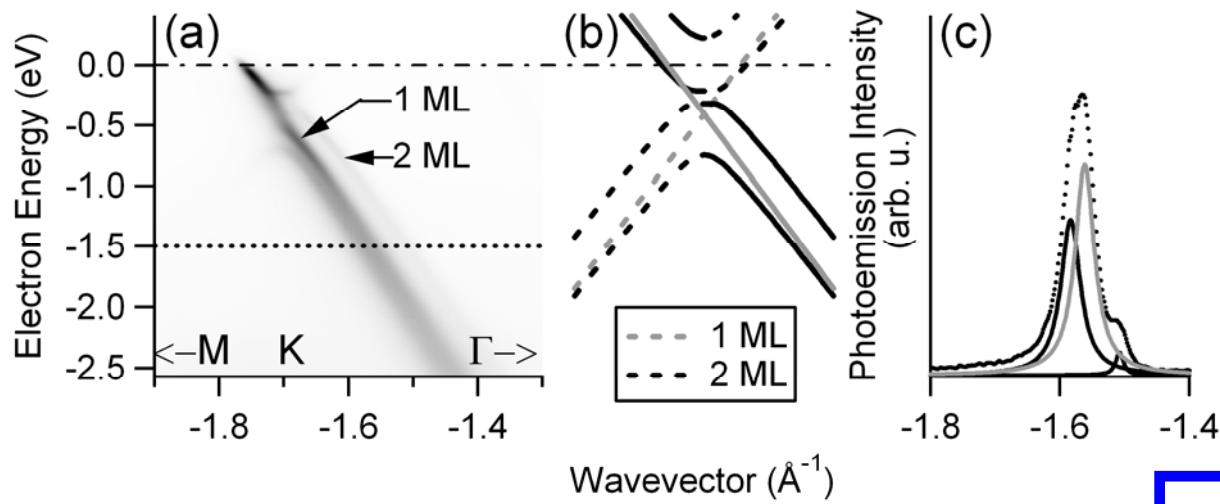
LEEM I-V Study of Graphene Film



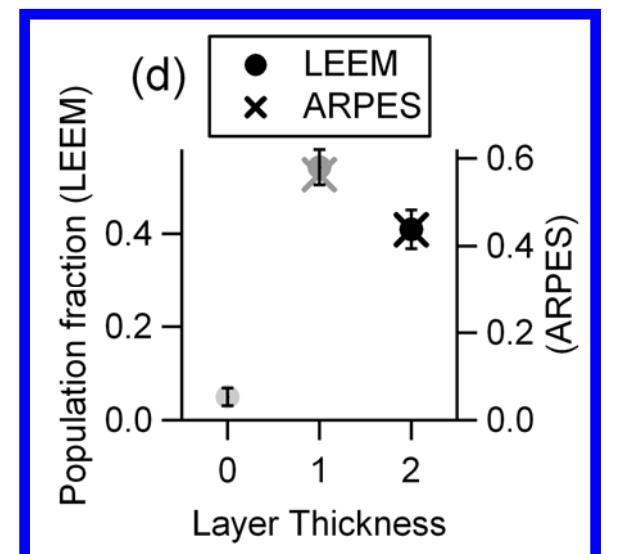
- Local interaction between layer +



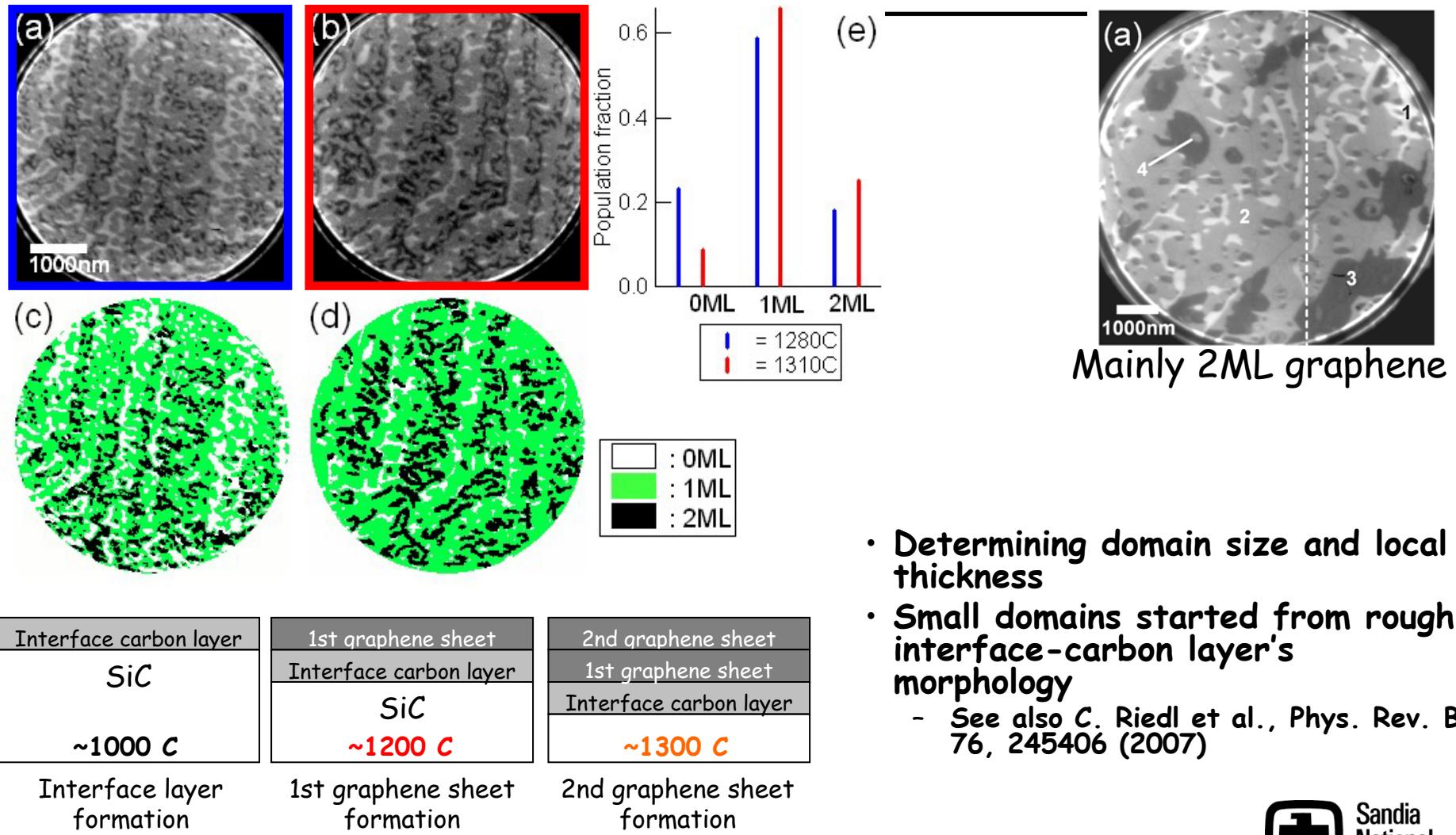
LEEM vs ARPES Thickness Calibration



- Very good agreement between LEEM and ARPES for thickness calibration

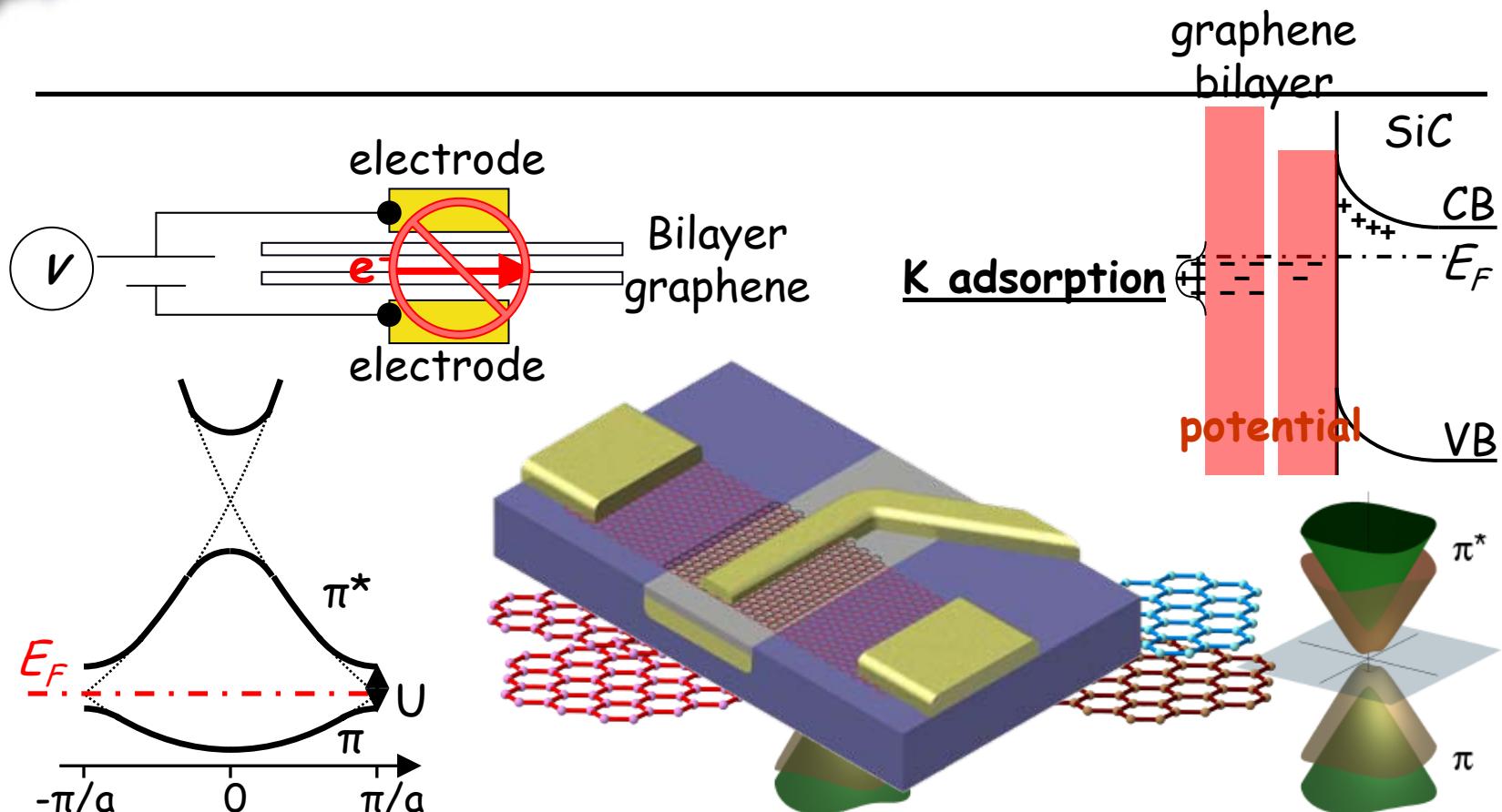


Morphology Evolution of Graphene Film



- Determining domain size and local thickness
- Small domains started from rough interface-carbon layer's morphology
 - See also C. Riedl et al., Phys. Rev. B 76, 245406 (2007)

Switching Functionality using Bilayer Graphene

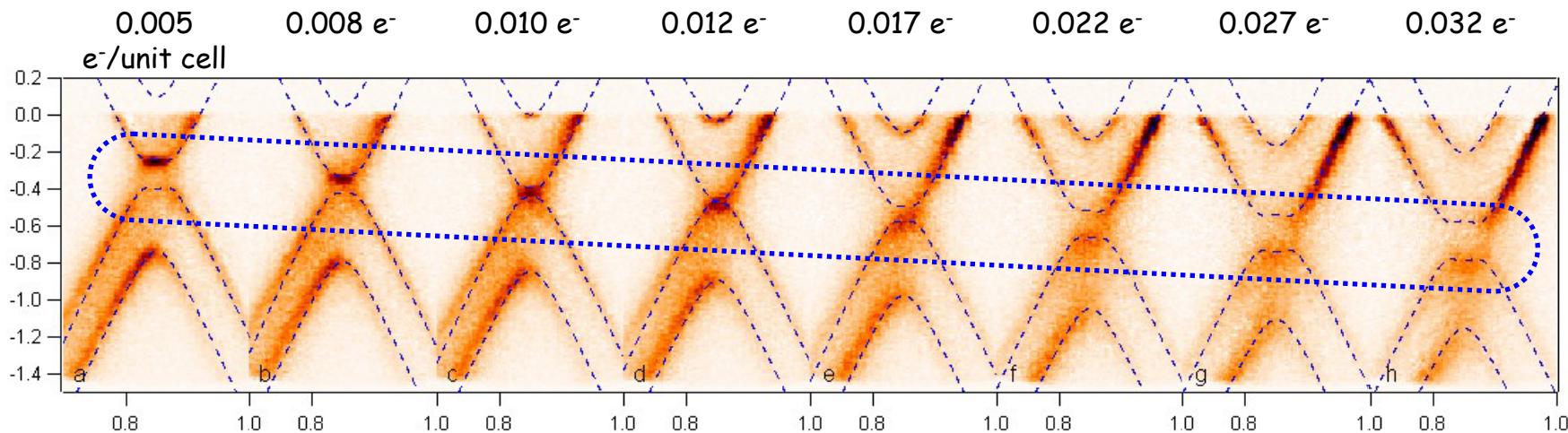


- Controlling gap between π and π^* bands by on-site Coulomb potential
 - Analogous to metal-insulator transition for transition metal oxides
 - Tuning Coulomb repulsion in Zaanen-Sawatzky-Allen diagram
- High current switching (~nA per atom)

Evolution of π Bands by Surface Doping

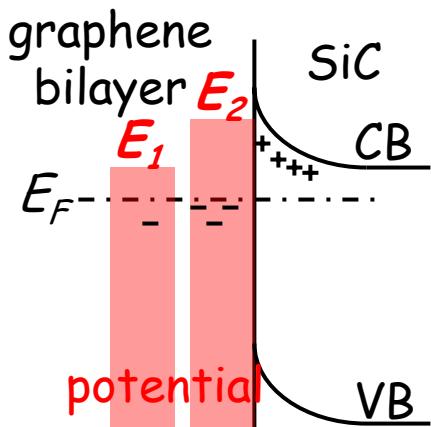
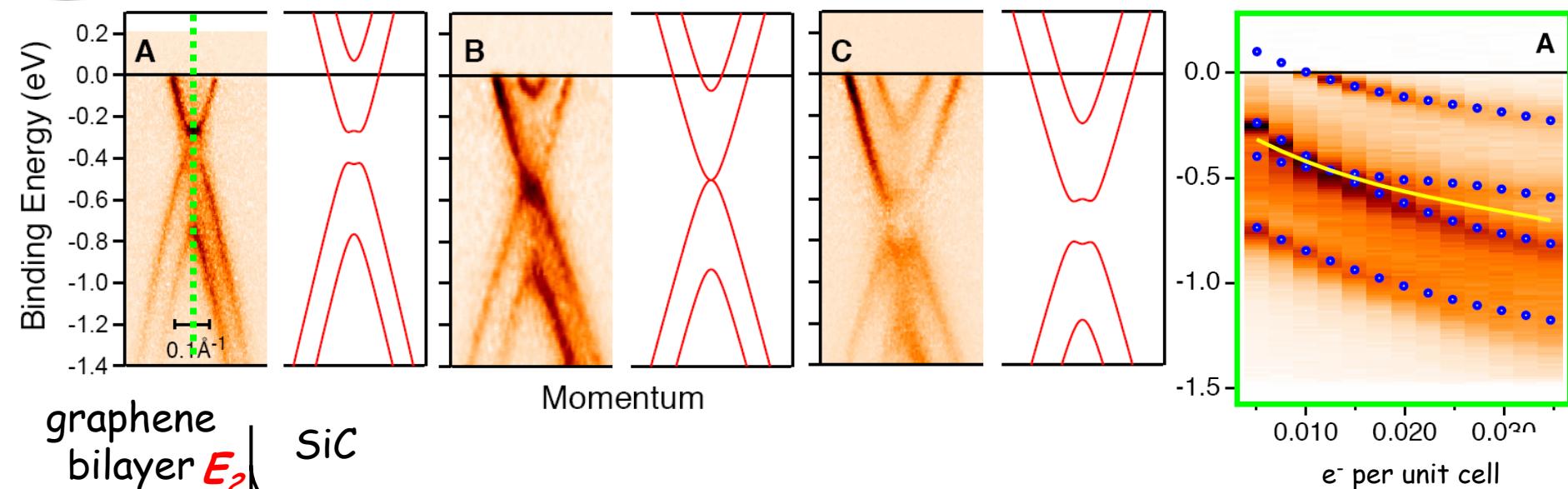
K

Dirac energy band structure



- Shift of π bands due to increased total carrier density
- Continuous closing/reopening of the gap

Closing and Opening of Gap between π and π^* Bands



- Control of potential difference
 - $E_1 = E_2$: no gap - delocalized
 - $E_1 \neq E_2$: gapped - localized
 - E_1 and E_2 extracted from TB calculation

TB Hamiltonian: McCann and Fal'ko, Phys. Rev. Lett. 96, 086805 (2006)



Sensitive Gas Sensor

- Shift of π bands due to increased total carrier density

Summary

- We have shown

- Electronic band structure of graphene

- Dirac fermion spectrum
 - Layer-dependent electronic band structure of single and multilayer
 - Potential and carrier concentration profiles in multilayer

- Morphology of graphene films on SiC

- Determining domain size and local thickness
 - Importance of interface-carbon layer on the formation of graphene

- Controlling the electronic structure in graphene bilayer

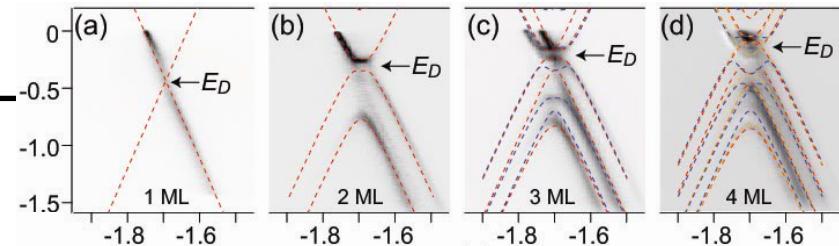
- Issues

- Small graphene domains

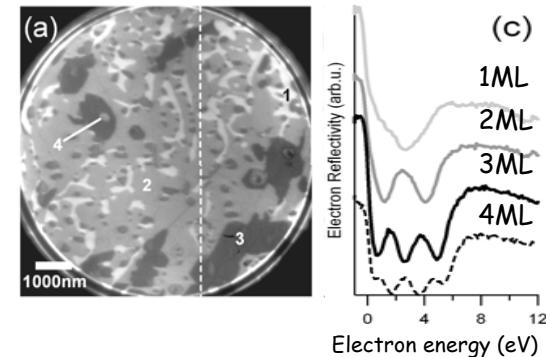
- We can determine
 - layer-dependent electronic structures
 - Symmetry breaking and gap control in bilayer
 - Too small for routine device fabrication

- Interface-carbon layer

- Symmetry breaking in monolayer (?)
 - Graphene formation process



structure of
profiles in



- Experimental tools

- ARPES
 - LEEM
 - Raman spectroscopy
 - IR spectroscopy
 - etc



Thank you!